Optoelectronic Devices (Photoelectronic Devices)

Optical Sources

Electrical - Light energy

EX: LED, LASER

Optical detectors(on)
Photodetectors

Light - Electrical energy

Ex: Photodiode, Solar cell

Optical detectors con Photodetectors

Since 1995

-> Photoconductive effect

Exi Photodiode

pin APD

>> Photovoltaic effect

EX: Solar cell

Optical Absorption * Photon absorption coefficient * EHP generation rate

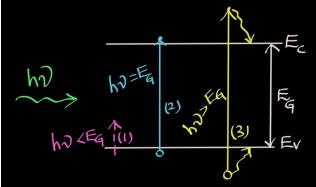


- (1) Photon interaction with Lattice -> heat
- (2) Photon interaction with acceptor -> No ETTP generation or donor impurities or defects
- (3) Photon interaction with value \rightarrow EHP generation electrons ($h \mathcal{D} \ge E_G$)

Photon Absorption coefficient (a)



* If ho< Eq, the light is transmitted through the semiconductor, it is said to be transporant.



The intensity of photon flux $-I_{\mathcal{D}}(x)$ (energy/ an^2-s)

* The energy absorbed per unit time in the distance dx is given by $I_{\mathcal{D}}(x)$ $I_{\mathcal{D}}$

$$\frac{d T_{\mathcal{V}}(x)}{dx} + d T_{\mathcal{V}}(x) = 0$$

$$\Rightarrow \int T_{\mathcal{V}}(x) = T_{\mathcal{V}} e \qquad T_{\mathcal{V}} = T_{\mathcal{V}}(x)|_{x=0}$$

$$\forall - \text{ Absorption coefficient}$$

$$\Rightarrow \text{ The absorption coefficient is a strong of photon energy (hv)}$$

$$\text{and energy gap (E_G) of the Semiconductor.}$$

-> Calculate the thickness of a semiconductor that will "absorb 90 percent" of the incident photon energy.

(i) $\lambda = 1 \mu m$ and (ii) $\lambda = 0.5 \mu m$



Assume the semiconductor is silicon, the absorption coefficient $\alpha \simeq 10^2$ cm¹ for $\alpha = 1$ mm and $\alpha \simeq 10^4$ cm⁻¹ for $\alpha = 0.5$ mm.

$$T_{\mathcal{V}} = T_{\mathcal{V}0} \stackrel{\text{d}}{=} \chi$$
At $\chi = d$, $T_{\mathcal{V}}(\chi = d) = 10 \%$, $T_{\mathcal{V}0} = 0.1$ $T_{\mathcal{V}0}$

$$T_{\mathcal{V}0} \stackrel{\text{d}}{=} d = 0.1$$

$$d = \frac{1}{\alpha} \ln(\frac{1}{0.1})$$

$$\chi = |\mu m_1| \quad d \approx 10^2 \text{ cm} \quad d = \frac{1}{10^2} \ln(\frac{1}{0.1}) = 0.023 \text{ cm}$$

$$\chi = 0.5 \mu m_1 \quad \chi \approx 0.4 \text{ cm} \quad d = \frac{1}{10^4} \ln(\frac{1}{0.1}) = 2.3 \mu m$$

Electron-Hole Pair Generation Rate



 $I_{\gamma}(x) \rightarrow \text{energy} | cm^2 - S$

ACE

(an) (energy an-s)

ACE

The rate at which, energy

(an) (energy an-s)

- * Each absorbed photon generates one EHP
- * The EMP generation rate is given by

$$\boxed{G^{1} = \frac{\alpha I_{\nu}(x)}{h\nu} \rightarrow \left(/ cm^{3} - S \right)}$$

$$\frac{I_{\mathcal{V}}(x)}{h\mathcal{V}} = \Phi(x) \rightarrow \text{Photon flux}$$

$$G^{1} = \mathcal{O}(x)$$



$$G = G_0 + G'$$

According the generation rate of EHPs given an incident intensity of photons. Consider Gats at T=300K. Assume ACE the photon intensity at a particular point is $I_{V}(x)=0.05$ W/and at a wavelength of 2=0.75 mm. The absorption coefficient for Gats at this wavelength is $d \approx 0.9 \times 10^{4}$ cm and $C=10^{7}$ s.

Photon energy
$$E(ev) = \frac{1.24}{\lambda (\mu m)} = \frac{1.24}{0.75} = 1.65 eV$$

$$G' = \frac{d \operatorname{I}_{V}(x)}{4 \operatorname{hW}}$$

$$G' = \frac{0.9 \times 10^{4} \times 0.05}{1.65 \times 1.6 \times (0^{-19})} = \frac{1.7 \times 10^{4} \operatorname{cm}^{3} - S}{1.65 \times 1.6 \times (0^{-19})}$$

$$\Rightarrow \operatorname{Ex (eu s carriers } Sp = Sn = S$$

$$S = G'C = \frac{1.7 \times 10^{4} \operatorname{cm}^{3}}{1.7 \times 10^{4} \operatorname{cm}^{3}}$$

$$= \frac{1.7 \times 10^{4} \operatorname{cm}^{3}}{1.7 \times 10^{4} \operatorname{cm}^{3}}$$



Photodetectors



- Photocon ductor
- AC

 > Long photodiode

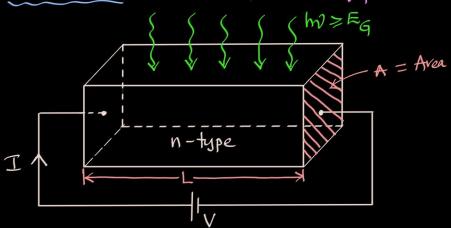
 > pin diode

 Photoconductive

 > APD Photodiode -
- Solar Cell Photovoltaic effect

Photoconductor -> The simplest from of photodetector





In the presence of excess carriers
$$\rightarrow \sigma = nq\mu_n + pq\mu_p$$

 $n = n_0 + Sn$ and $p = P_0 + Sp$ $Sn = Sp = S$
 $\sigma = nq\mu_n + pq\mu_p = (n_0 + S)q\mu_n + (P_0 + S)q\mu_p$
 $= (n_0 q\mu_n + p_0 q\mu_p) + (Sq\mu_n + Sq\mu_p)$
 $\sigma = \sigma_0 + \Delta\sigma$ (or) $\Delta\sigma = \sigma_L = qS(\mu_n + \mu_p)$
 $\sigma = \sigma_0 + \sigma_L$

-> Assume the semiconductor is n-type



$$J = \sigma E = (\sigma_0 + \sigma_L)E = \sigma_0 E + \sigma_L E$$
 $J = J_0 + J_L$, $J_L - Photocurrent$ density

 $J_L = \sigma_L E = \Delta \sigma E$
 $I_L = AJ_L = A\sigma_L E = A9S(Mn + Mp)E$
 $I_L = A9GC_p(Mn + Mp)E$
 $I_L = A9GC_p(Mn + Mp)E$

The transit time of the electron, it is the time taken by the electron to travel a distance 'L'
$$t_{n} = \frac{L}{v_{n}} = \frac{L}{M_{n}E} \Rightarrow M_{n}E = \frac{L}{t_{n}}$$

$$\rightarrow$$
 Consider $I_L = 96 C_p \left(1 + \frac{Mp}{Mn}\right) M_n \in A$

$$\Rightarrow \left[I_{L} = 96 \left(\frac{\Gamma_{p}}{t_{n}} \right) \left(1 + \frac{M_{p}}{M_{N}} \right) AL \right]$$

→ Photoconductor gain — It is the ratio of the rate at which change is collected by the contacts to the rate at which change is generated within the photoconductor ([ph.)



$$\int_{Ph} = \frac{I_L}{q \, G' A L} = \frac{T_P}{t_N} \left(1 + \frac{Mp}{Mn} \right)$$

Consider an n-type silicon photoconductor with a length $L = 100 \mu m$, cross-sectional area $A = 10^{-7} \text{ cm}^2$ and ACI minority carrier life time $T_p = 10^{-6} \text{ s}$. Let the applied voltage be V = 10 Volts. Calculate the photoconductor gain. Given that $\mu_n = 1350 \text{ cm}^2/\text{V-s}$ and $\mu_p = 480 \text{ cm}^2/\text{V-s}$.

$$\Gamma_{ph} = \frac{IL}{96^{\prime}AL} = \frac{C_{p}}{t_{n}} \left(1 + \frac{M_{p}}{M_{n}}\right)$$

$$t_{n} = \frac{L}{9n} = \frac{L}{M_{n}E} = \frac{L}{M_{n}V/L} = \frac{2}{M_{n}V} \left(::E = \frac{V}{L} \right)$$

$$= \frac{100 \times 10^{4}}{1350 \times 10} = 7.41 \text{ ns}$$

$$\Gamma_{ph} = \frac{10^{-6}}{7.41 \times 10^{9}} \left(1 + \frac{480}{1350}\right) = 1.83 \times 10^{2}$$

$$= 183$$